Notice of References Cited Application/Control No. 10/754,151 Examiner Art Unit Michael Band Applicant(s)/Patent Under Reexamination YAKSHIN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	. Name	Classification
*	Α	US-5,492,605	02-1996	Pinarbasi, Mustafa	204/192.11
*	В	US-6,635,155 B2	10-2003	Miyamura et al.	204/192.13
*	С	US-2003/0024808 A1	02-2003	Donohue et al.	204/192.17
*	D	US-6,190,511 B1	02-2001	Wei, David T.	204/192.11
*	E	US-5,431,794	07-1995	Matsumaru et al.	204/192.14
*	F	US-H0,001,933 H	01-2001	Zabinski et al.	204/298.26
*	G	US-5,938,897	08-1999	Isao et al.	204/192.15
*	Н	US-6,893,542 B1	05-2005	Chen, Ga-Lane	204/192.2
*	1	US-4,957,604	09-1990	Steininger, Helmut	204/192.16
*	J	US-6,878,241 B2	04-2005	Yamaguchi et al.	204/192.12
*	к	US-5,643,633 A	07-1997	Telford et al.	427/255.17
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0			,		
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gupta, S.; Ruspini, A.; and Fregau, M. Highly Uniform Dielectric Films Using a Combined Linear Scanning, Velocity Profiling, and Planetary Rotating Motion. Vacuum Technology & Coating [online], December 2002 [retrieved 2007-04-17]. Retrieved from the Internet: <url:http: file_3.pdf="" www.kdf.com=""></url:http:>
	٧	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.